

**Search Notes**

Application/Control No.

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Examiner

Hai V. Nguyen

Applicant(s)/Patent under  
Reexamination

HARTMANN ET AL.

Art Unit

2142

**SEARCHED**

Class	Subclass	Date	Examiner
709	203	6/14/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
715	744	6/14/2006	HN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR